

## SPECIFICATION AMENDMENTS

On page 3, please replace the paragraph beginning on line 11 with the following amended paragraph.

a1  
This approach is limited, however, because current AC I/O loop-back based structural tests cannot screen marginal (VIH/VIL) levels defects since there are no DFT knobs to change the amplitude of the driven signal. Additionally, an output level defect can be hidden by an input level defect since the two are exercised together.

On page 9, please replace the paragraph beginning on line 1 with the following amended paragraph.

a2  
applying one value for the configuration bits ~~152~~ 150 to the internal voltage generators 140, 142, and 144 causes the internal voltage generators 140, 142, and 144 to drive a voltage level the receivers 134, 136, and 138 should interpret as a logical "one." Applying another value for the configuration bits 150 to the internal voltage generators 140, 142, and 144 causes the internal voltage generators 140, 142, and 144 to drive a voltage level the receivers 134, 136, and 138 should interpret as a logical "zero." Of course, the configuration bits 150 may specify several different values that may be interpreted a logical "zeros" and/or a logical "ones."